

REVISIONS

LTR	DESCRIPTION	DATE (YR-MO-DA)	APPROVED

REV																				
SHEET																				
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SHEET	15	16	17	18																
REV STATUS OF SHEETS	REV																			
	SHEET			1	2	3	4	5	6	7	8	9	10	11	12	13	14			

PMIC N/A	PREPARED BY Steve Duncan	<p align="center">DEFENSE SUPPLY CENTER COLUMBUS COLUMBUS, OHIO 43218-3990 http://www.dsc.dla.mil</p>																		
<p align="center">STANDARD MICROCIRCUIT DRAWING</p> <p align="center">THIS DRAWING IS AVAILABLE FOR USE BY ALL DEPARTMENTS AND AGENCIES OF THE DEPARTMENT OF DEFENSE</p> <p align="center">AMSC N/A</p>	CHECKED BY Greg Cecil																			
	APPROVED BY Raymond Monnin	<p align="center">MICROCIRCUIT, HYBRID, LINEAR, 64 CHANNEL, ANALOG MULTIPLEXER</p>																		
	DRAWING APPROVAL DATE 05-03-03																			
	REVISION LEVEL		<table border="1"> <tr> <td>SIZE A</td> <td>CAGE CODE 67268</td> <td>5962-05209</td> </tr> </table>	SIZE A	CAGE CODE 67268	5962-05209														
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		SHEET	1 OF 18																	

1.2.4 Case outline(s). The case outline(s) are as designated in MIL-STD-1835 and as follows:

<u>Outline letter</u>	<u>Descriptive designator</u>	<u>Terminals</u>	<u>Package style</u>
X	See figure 1	96	Ceramic quad flat pack

1.2.5 Lead finish. The lead finish shall be as specified in MIL-PRF-38534.

1.3 Absolute maximum ratings. ^{1/}

Positive supply voltage between +V _{CC} and GND	+20 V dc
Negative supply voltage between -V _{EE} and GND	-20 V dc
V _{REF} to GND	+20 V dc
Digital input overvoltage range:	
V _{EN} (pins 5, 6, 91, and 92)	(< V _{REF} + 4)V, (> GND - 4)V
V _A (pins 1, 3, 93, and 95)	(< V _{REF} + 4)V, (> GND - 4)V
V _B (pins 2, 4, 94, and 96)	(< V _{REF} + 4)V, (> GND - 4)V
Analog input overvoltage range	-18 V dc ≤ V _S ≤ +18 V dc
Power dissipation (P _D)	100 mW
Thermal resistance junction-to-case (θ _{JC})	5.5°C/W ^{2/}
Storage temperature	-55°C to +150°C
Lead temperature (soldering, 10 seconds)	+300°C

1.4 Recommended operating conditions.

Positive supply voltage (+V _{CC}) ^{3/}	+15 V dc
Negative supply voltage (-V _{EE}) ^{3/}	-15 V dc
V _{REF} ^{3/}	+5 V dc
Logic low level voltage (V _{AL})	+0.8 V dc
Logic high level voltage (V _{AH})	+4.0 V dc
Case operating temperature range (T _C)	-55°C to +125°C

2. APPLICABLE DOCUMENTS

2.1 Government specification, standards, and handbooks. The following specification, standards, and handbooks form a part of this drawing to the extent specified herein. Unless otherwise specified, the issues of these documents are those listed in the issue of the Department of Defense Index of Specifications and Standards (DoDISS) and supplement thereto, cited in the solicitation.

SPECIFICATION

DEPARTMENT OF DEFENSE

MIL-PRF-38534 - Hybrid Microcircuits, General Specification for.

STANDARDS

DEPARTMENT OF DEFENSE

MIL-STD-883 - Test Method Standard Microcircuits.
 MIL-STD-1835 - Interface Standard Electronic Component Case Outlines.

- ^{1/} Stresses above the absolute maximum ratings may cause permanent damage to the device. Extended operation at the maximum levels may degrade performance and affect reliability.
^{2/} Based on the maximum power dissipation spread over all five die.
^{3/} Supply voltages must be applied simultaneously or with the +5 V reference supply first and then the ±15 V supplies.

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HANDBOOKS

DEPARTMENT OF DEFENSE

- MIL-HDBK-103 - List of Standard Microcircuit Drawings.
- MIL-HDBK-780 - Standard Microcircuit Drawings.

(Copies of these documents are available online at <http://assist.daps.dla.mil/quicksearch/> or <http://assist.daps.dla.mil> or from the Standardization Document Order Desk, 700 Robbins Avenue, Building 4D, Philadelphia, PA 19111-5094.)

2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing takes precedence. Nothing in this document, however, supersedes applicable laws and regulations unless a specific exemption has been obtained.

3. REQUIREMENTS

3.1 Item requirements. The individual item performance requirements for device classes D, E, G, H, and K shall be in accordance with MIL-PRF-38534. Compliance with MIL-PRF-38534 shall include the performance of all tests herein or as designated in the device manufacturer's Quality Management (QM) plan or as designated for the applicable device class. The manufacturer may eliminate, modify or optimize the tests and inspections herein, however the performance requirements as defined in MIL-PRF-38534 shall be met for the applicable device class. In addition, the modification in the QM plan shall not affect the form, fit, or function of the device for the applicable device class.

3.2 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-PRF-38534 and herein.

3.2.1 Case outline(s). The case outline(s) shall be in accordance with 1.2.4 herein and figure 1.

3.2.2 Terminal connections. The terminal connections shall be as specified on figure 2.

3.2.3 Truth table(s). The truth table(s) shall be as specified on figure 3.

3.2.4 Switching waveform(s). The switching waveform(s) shall be as specified on figure 4.

3.2.5 Block diagram. The block diagram shall be as specified on figure 5.

3.3 Electrical performance characteristics. Unless otherwise specified herein, the electrical performance characteristics are as specified in table I and shall apply over the full specified operating temperature range.

3.4 Electrical test requirements. The electrical test requirements shall be the subgroups specified in table II. The electrical tests for each subgroup are defined in table I.

3.5 Marking of device(s). Marking of device(s) shall be in accordance with MIL-PRF-38534. The device shall be marked with the PIN listed in 1.2 herein. In addition, the manufacturer's vendor similar PIN may also be marked.

3.6 Data. In addition to the general performance requirements of MIL-PRF-38534, the manufacturer of the device described herein shall maintain the electrical test data (variables format) from the initial quality conformance inspection group A lot sample, for each device type listed herein. Also, the data should include a summary of all parameters manually tested, and for those which, if any, are guaranteed. This data shall be maintained under document revision level control by the manufacturer and be made available to the preparing activity (DSCC-VA) upon request.

3.7 Certificate of compliance. A certificate of compliance shall be required from a manufacturer in order to supply to this drawing. The certificate of compliance (original copy) submitted to DSCC-VA shall affirm that the manufacturer's product meets the performance requirements of MIL-PRF-38534 and herein.

3.8 Certificate of conformance. A certificate of conformance as required in MIL-PRF-38534 shall be provided with each lot of microcircuits delivered to this drawing.

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TABLE I. Electrical performance characteristics.

Test	Symbol	Conditions <u>1/ 2/</u> -55°C ≤ T _C ≤ +125°C unless otherwise specified	Group A subgroups	Device type	Limits		Unit
					Min	Max	
Supply currents	+I _{CC}	V _{EN(0-63)} = V _{A(0-3)A} = V _{A(0-1)C} = 0	1,2,3	01,02	0.25	2.5	mA
	-I _{CC}	V _{EN(0-63)} = V _{A(0-3)A} = V _{A(0-1)C} = 0	1,2,3	01,02	-2.5	-0.25	mA
	+I _{SBY}	V _{EN(0-63)} = 4 V, V _{A(0-3)A} = V _{A(0-1)C} = 0 <u>3/</u>	1,2,3	01,02	0.25	2.5	mA
	-I _{SBY}	V _{EN(0-63)} = 4 V, V _{A(0-3)A} = V _{A(0-1)C} = 0 <u>3/</u>	1,2,3	01,02	-2.5	-0.25	mA
Address input currents	I _{AL(0-1)C}	V _A = 0 V <u>2/</u>	1,2,3	01,02	-1	1	μA
	I _{AH(0-1)C}	V _A = 5 V <u>2/</u>	1,2,3	01,02	-1	1	μA
	I _{AL(0-3)A}	V _A = 0 V <u>2/</u>	1,2,3	01,02	-4	4	μA
	I _{AH(0-3)A}	V _A = 5 V <u>2/</u>	1,2,3	01,02	-4	4	μA
Enable input current	I _{ENL(0-15)}	V _{EN(0-15)} = 0 V	1,2,3	01,02	-1	1	μA
	I _{ENH(0-15)}	V _{EN(0-15)} = 5 V	1,2,3	01,02	-1	1	μA
	I _{ENL(16-31)}	V _{EN(0-15)} = 0 V	1,2,3	01,02	-1	1	μA
	I _{ENH(16-31)}	V _{EN(0-15)} = 5 V	1,2,3	01,02	-1	1	μA
	I _{ENL(32-47), I_{ENL(MuxMon)}}	V _{EN(0-15)} = 0 V	1,2,3	01,02	-2	2	μA
	I _{ENH(32-47), I_{ENH(MuxMon)}}	V _{EN(0-15)} = 5 V	1,2,3	01,02	-2	2	μA
	I _{ENL(48-63)}	V _{EN(0-15)} = 0 V	1,2,3	01,02	-1	1	μA
	I _{ENH(48-63)}	V _{EN(0-15)} = 5 V	1,2,3	01,02	-1	1	μA

See footnotes at end of table.

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TABLE I. Electrical performance characteristics - Continued.

Test	Symbol	Conditions <u>1/ 2/</u> -55°C ≤ T _C ≤ +125°C unless otherwise specified	Group A subgroups	Device type	Limits		Unit
					Min	Max	
Positive input leakage current (CH0-CH63)	+I _{SOFFOUTPUT(ALL)}	V _{IN} = +10 V, V _{EN} = 4 V, output and all unused inputs = -10 V <u>4/ 5/</u>	1,2,3	01	-100	+700	nA
				02	-100	+200	
	+I _{SOFFCURRENT(ALL)}	V _{IN} = +10 V, V _{EN} = 4 V, output and all unused inputs = -10 V <u>4/ 5/</u>	1,2,3	01	-100	+700	nA
				02	-100	+200	
Negative input leakage current (CH0-CH63)	-I _{SOFFOUTPUT(ALL)}	V _{IN} = -10 V, V _{EN} = 4 V, output and all unused inputs = +10 V <u>4/ 5/</u>	1,2,3	01	-100	+700	nA
				02	-100	+200	
	-I _{SOFFCURRENT(ALL)}	V _{IN} = -10 V, V _{EN} = 4 V, output and all unused inputs = +10 V <u>4/ 5/</u>	1,2,3	01	-100	+700	nA
				02	-100	+200	
Output leakage current outputs (pins 25, 26, 68, 69, and 70 <u>3/</u> - applies to pin 69 (Mux Monitor) only	+I _{DOFFOUTPUT(ALL)}	V _{IN} = +10 V, V _{EN} = 4 V, output and all unused inputs = -10 V <u>5/ 6/</u>	1,2,3	01,02	-100	+100	nA
	+I _{DOFFCURRENT(ALL)}	V _{IN} = +10 V, V _{EN} = 4 V, output and all unused inputs = -10 V <u>5/ 6/</u>	1,2,3	01,02	-100	+100	nA
	-I _{DOFFOUTPUT(ALL)}	V _{IN} = -10 V, V _{EN} = 4 V, output and all unused inputs = +10 V <u>5/ 6/</u>	1,2,3	01,02	-100	+100	nA
	-I _{DOFFCURRENT(ALL)}	V _{IN} = -10 V, V _{EN} = 4 V, output and all unused inputs = +10 V <u>5/ 6/</u>	1,2,3	01,02	-100	+100	nA
Input clamped voltage (CH0-CH63)	+V _{CLMP(0-63)}	V _{EN} = 4 V, all unused inputs are open <u>5/</u>	1	01	18.0	23.0	V
			2		18.0	23.5	
			3		17.5	22.5	
	-V _{CLMP(0-63)}	V _{EN} = 4 V, all unused inputs are open <u>5/</u>	1	01	-23.0	-18.0	V
			2		-23.5	-18.0	
			3		-22.5	-17.5	

See footnotes at end of table.

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TABLE I. Electrical performance characteristics - Continued.

Test	Symbol	Conditions <u>1/</u> <u>2/</u> -55°C ≤ T _C ≤ +125°C unless otherwise specified	Group A subgroups	Device type	Limits		Unit
					Min	Max	
Switch ON resistance outputs (pins 25, 26, 68, 69, and 70)	R _{DS(ON)(0-63)}	V _{IN} = +15 V, V _{EN} = 0.8 V, I _{OUT} = -1 mA <u>4/</u> <u>5/</u> <u>7/</u>	1,2,3	01,02	500	3000	Ω
	R _{DS(ON)(0-63)}	V _{IN} = +5 V, V _{EN} = 0.8 V, I _{OUT} = -1 mA <u>4/</u> <u>5/</u> <u>7/</u>	1,2,3	01,02	500	3000	Ω
	R _{DS(ON)(0-63)}	V _{IN} = -5 V, V _{EN} = 0.8 V, I _{OUT} = +1 mA <u>3/</u> <u>4/</u> <u>5/</u> <u>7/</u>	1,2,3	01,02	500	3000	Ω
Switching tests	t _{ONA}	R _L = 10 kΩ, C _L = 50 pF, See figure 4.	9,10,11	01,02	10	1500	ns
	t _{OFFA}	R _L = 10 kΩ, C _L = 50 pF, See figure 4.	9,10	01,02	10	2000	ns
			11		10	5000	
	t _{ONEN}	R _L = 1 kΩ, C _L = 50 pF, See figure 4.	9,10,11	01,02	10	1500	ns
t _{OFFEN}	R _L = 1 kΩ, C _L = 50 pF, See figure 4.	9,10,11	01,02	10	1000	ns	

1/ +V_{CC} = +15 V dc, -V_{EE} = -15 V dc, and V_{REF} = +5 V dc, unless otherwise specified.

2/ Measure inputs sequentially. Ground all unused inputs. V_A is the applied input voltage to the address lines A(0-3) and C(0-1).

3/ If not tested, shall be guaranteed to the limits specified in table I.

4/ V_{IN} is the applied input voltage to the input channels (CH0-CH63).

5/ V_{EN} is the applied input voltage to the enable lines \overline{EN} (0-15), \overline{EN} (16-31), \overline{EN} (32-47), and \overline{EN} (48-63).

6/ V_{OUT} is the applied input voltage to the output lines (OUTPUT(1-15), OUTPUT(16-31), OUTPUT(32-47), OUTPUT(48-63)).

7/ Negative current is the current flowing out of each of the pins. Positive current is the current flowing into each of the pins.

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Case outline X.

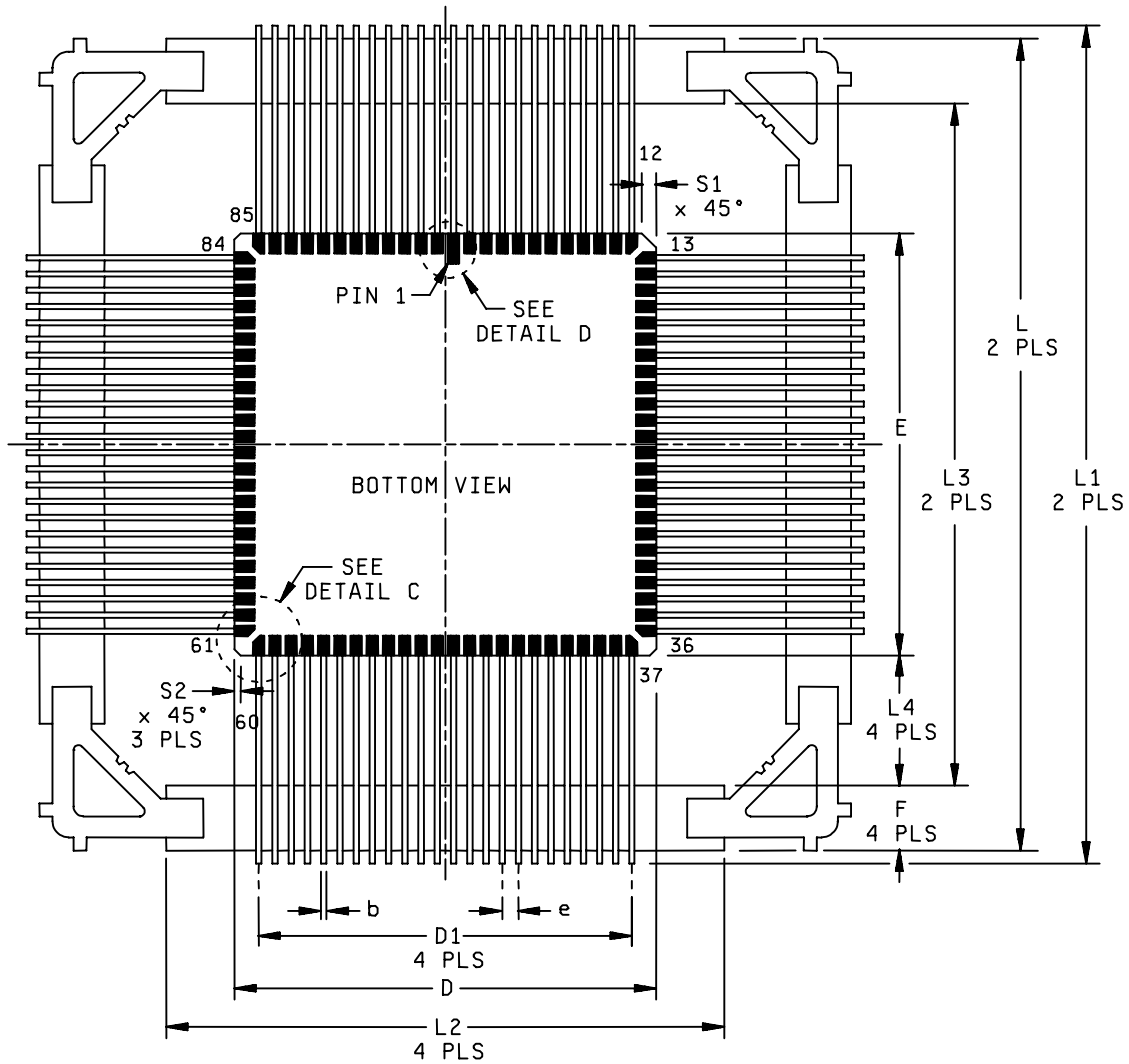


FIGURE 1. Case outline(s).

<p>STANDARD MICROCIRCUIT DRAWING</p> <p>DEFENSE SUPPLY CENTER COLUMBUS COLUMBUS, OHIO 43218-3990</p>	<p>SIZE A</p>		<p>5962-05209</p>
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Case outline X - Continued.

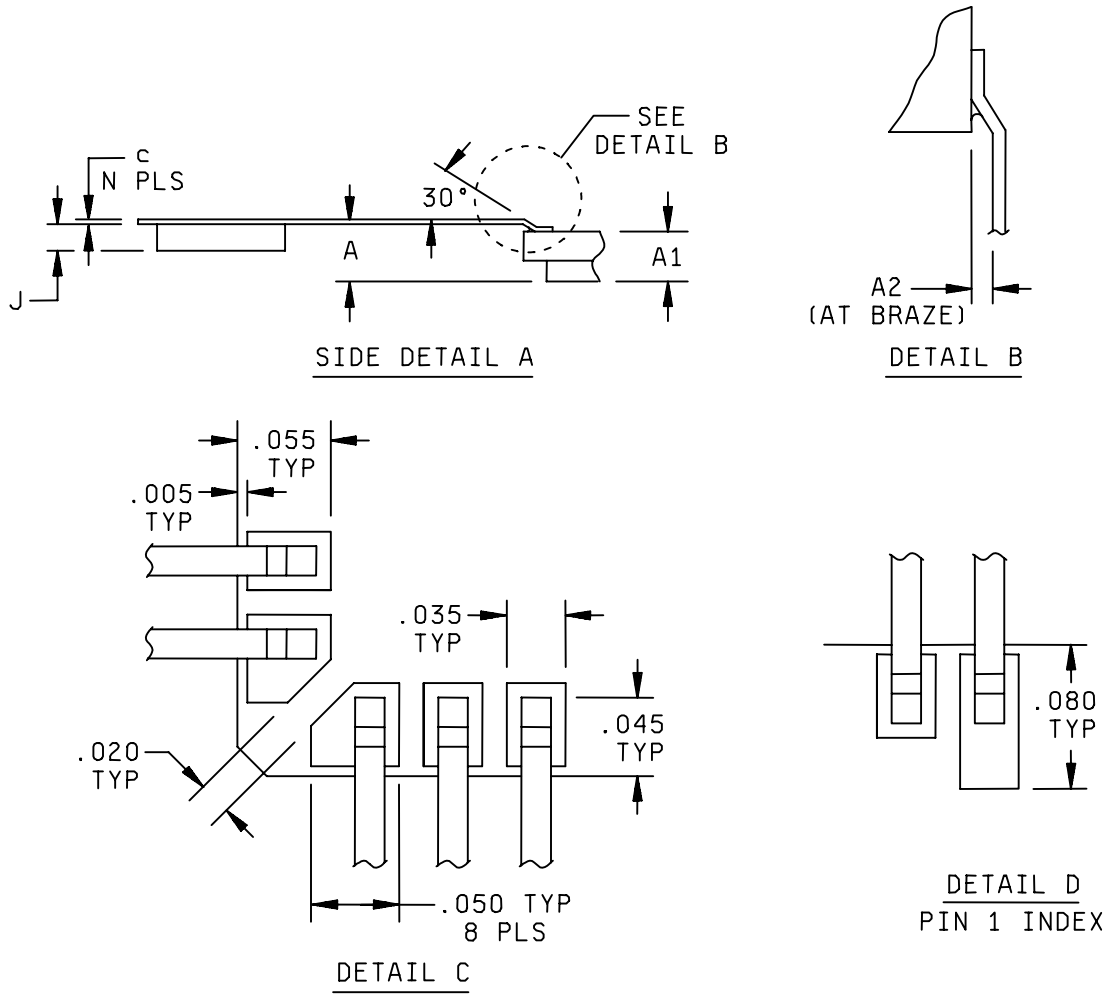


FIGURE 1. Case outline(s) - Continued.

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Case outline X - Continued.

Symbol	Inches		Millimeters	
	Min	Max	Min	Max
A		.200		5.08
A1		.180		4.57
A2	.005	.011	0.13	0.28
b	.0135	.0195	0.34	0.50
c	.005	.008	0.13	0.20
D/E	1.287	1.313	32.69	33.35
D1	1.145	1.155	29.08	29.34
e	0.050 BSC		1.27 BSC	
F	.200 TYP		5.08 TYP	
J	.035 TYP		0.89 TYP	
L	2.490	2.510	63.25	63.75
L1		2.580		65.53
L2	1.700	1.740	43.18	44.20
L3	2.090	2.110	53.09	53.59
L4	.400 TYP		10.16 TYP	
N	96		96	
S1	.030 TYP		0.76 TYP	
S2	.015 TYP		0.38 TYP	

NOTES:

1. Pin 1 is indicated by an ESD triangle on top of the package and by an index on the bottom of the package.
2. The U.S. preferred system of measurement is the metric SI. This item was designed using inch-pound units of measurement. In case of problems involving conflicts between the metric and inch-pound units, the inch-pound units shall rule.
3. N equals 96, the total number of leads on the package.
4. Pin numbers are for reference only.

FIGURE 1. Case outline(s) - Continued.

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Device types	01,02				
Case outline	X				
Terminal number	Terminal symbol	Terminal number	Terminal symbol	Terminal number	Terminal symbol
1	A2	33	CH 11	65	CH 49
2	C0	34	CH 27	66	CH 48
3	A3	35	CH 12	67	NC
4	C1	36	CH 28	68	OUTPUT V(48-63)
5	\overline{EN} 0-15	37	CH 13	69	MUX MONITOR
6	\overline{EN} 16-31	38	CH 29	70	OUTPUT V(32-47)
7	CH 0	39	CH 14	71	GND
8	CH 16	40	CH 30	72	GND
9	CH 1	41	CH 15	73	CH 47
10	CH 17	42	CH 31	74	CH 46
11	CH 2	43	NC	75	CH 45
12	CH 18	44	+V _{CC}	76	CH 44
13	CH 3	45	NC	77	CH 43
14	CH 19	46	-V _{EE}	78	CH 42
15	CH 4	47	NC	79	CH 41
16	CH 20	48	V _{REF}	80	CH 40
17	CH 5	49	NC	81	CH 39
18	CH 21	50	Case GND	82	CH 38
19	CH 6	51	CH 63	83	CH 37
20	CH 22	52	CH 62	84	CH 36
21	CH 7	53	CH 61	85	CH 35
22	CH 23	54	CH 60	86	CH 34
23	GND	55	CH 59	87	CH 33
24	GND	56	CH 58	88	CH 32
25	OUTPUT V(0-15)	57	CH 57	89	GND
26	OUTPUT V(16-31)	58	CH 56	90	GND
27	CH 8	59	CH 55	91	\overline{EN} 48-63
28	CH 24	60	CH 54	92	\overline{EN} 32-47
29	CH 9	61	CH 53	93	A0
30	CH 25	62	CH 52	94	NC
31	CH 10	63	CH 51	95	A1
32	CH 26	64	CH 50	96	NC

NOTE: NC is a no connect pin. NC pins should be grounded to eliminate or minimize electrostatic discharge (ESD) or static buildup.

FIGURE 2. Terminal connections.

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Truth table (CH 0 - CH 15) and (CH 16 - CH 31)							
A3	A2	A1	A0	$\overline{\text{EN}}$ (0-15)	"ON" Channel <u>1/</u>	$\overline{\text{EN}}$ (16-31)	"ON" Channel <u>2/</u>
X	X	X	X	H	None	H	None
L	L	L	L	L	CH 0	L	CH 16
L	L	L	H	L	CH 1	L	CH 17
L	L	H	L	L	CH 2	L	CH 18
L	L	H	H	L	CH 3	L	CH 29
L	H	L	L	L	CH 4	L	CH 20
L	H	L	H	L	CH 5	L	CH 21
L	H	H	L	L	CH 6	L	CH 22
L	H	H	H	L	CH 7	L	CH 23
H	L	L	L	L	CH 8	L	CH 24
H	L	L	H	L	CH 9	L	CH 25
H	L	H	L	L	CH 10	L	CH 26
H	L	H	H	L	CH 11	L	CH 27
H	H	L	L	L	CH 12	L	CH 28
H	H	L	H	L	CH 13	L	CH 29
H	H	H	L	L	CH 14	L	CH 30
H	H	H	H	L	CH 15	L	CH 31

- 1/ Between CH (0-15) and output (0-15).
2/ Between CH (16-31) and output (16-31).

Truth table (CH 32 - CH 47) and (CH 48 - CH 63)							
A3	A2	A1	A0	$\overline{\text{EN}}$ (32-47)	"ON" Channel <u>1/</u>	$\overline{\text{EN}}$ (47-63)	"ON" Channel <u>2/</u>
X	X	X	X	H	None	H	None
L	L	L	L	L	CH 32	L	CH 48
L	L	L	H	L	CH 33	L	CH 49
L	L	H	L	L	CH 34	L	CH 50
L	L	H	H	L	CH 35	L	CH 51
L	H	L	L	L	CH 36	L	CH 52
L	H	L	H	L	CH 37	L	CH 53
L	H	H	L	L	CH 38	L	CH 54
L	H	H	H	L	CH 39	L	CH 55
H	L	L	L	L	CH 40	L	CH 56
H	L	L	H	L	CH 41	L	CH 57
H	L	H	L	L	CH 42	L	CH 58
H	L	H	H	L	CH 43	L	CH 59
H	H	L	L	L	CH 44	L	CH 60
H	H	L	H	L	CH 45	L	CH 61
H	H	H	L	L	CH 46	L	CH 62
H	H	H	H	L	CH 47	L	CH 63

- 1/ Between CH (32-47) and output (32-47) and current (32-47).
2/ Between CH (48-63) and output (48-63) and current (48-63).

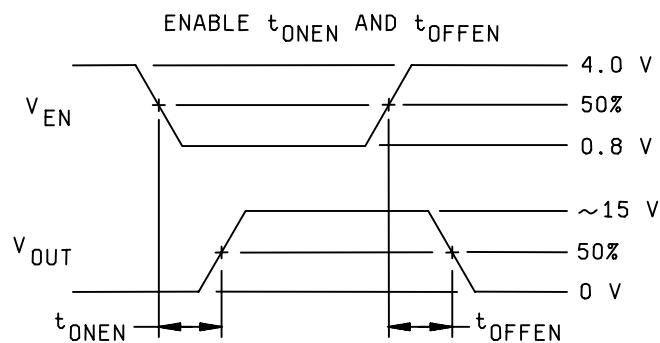
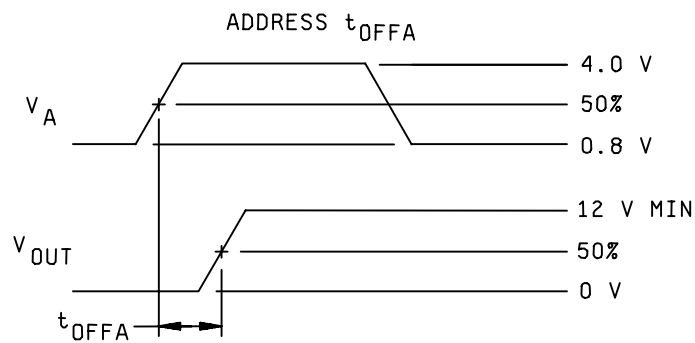
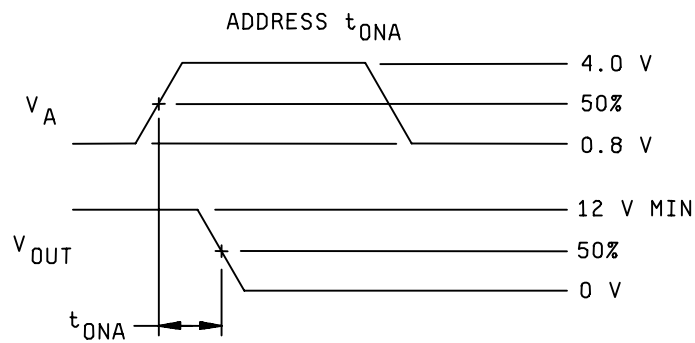
FIGURE 3. Truth table(s).

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Truth table (Mux Output Monitor)			
C1	C0	$\overline{\text{EN}}$ (32-47)	"ON" Channel
X	X	H	None
L	L	L	Output channels 0-15
L	H	L	Output channels 16-31
H	L	L	Output channels 32-47
H	H	L	Output channels 48-63

FIGURE 3. Truth table(s) - Continued.

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NOTE: $f = 10 \text{ kHz}$, duty cycle = 50%.

FIGURE 4. Switching test waveform(s).

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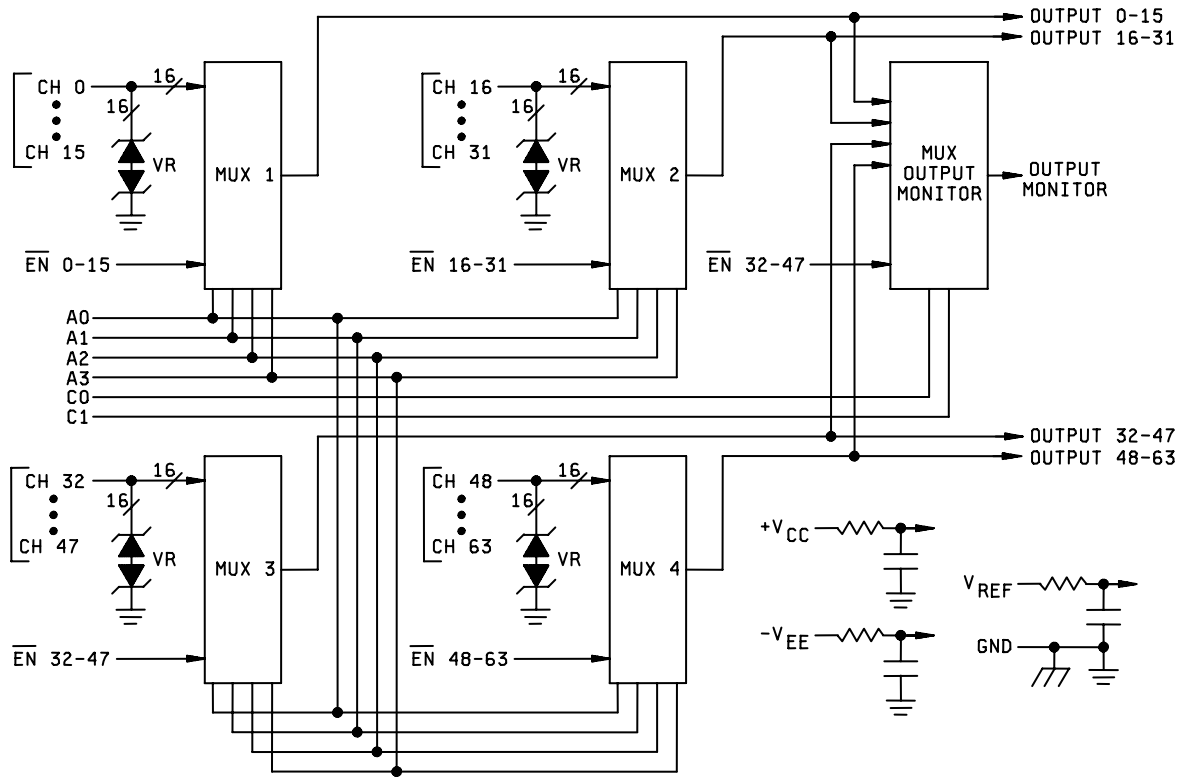


FIGURE 5. Block diagram, (Device type 01).

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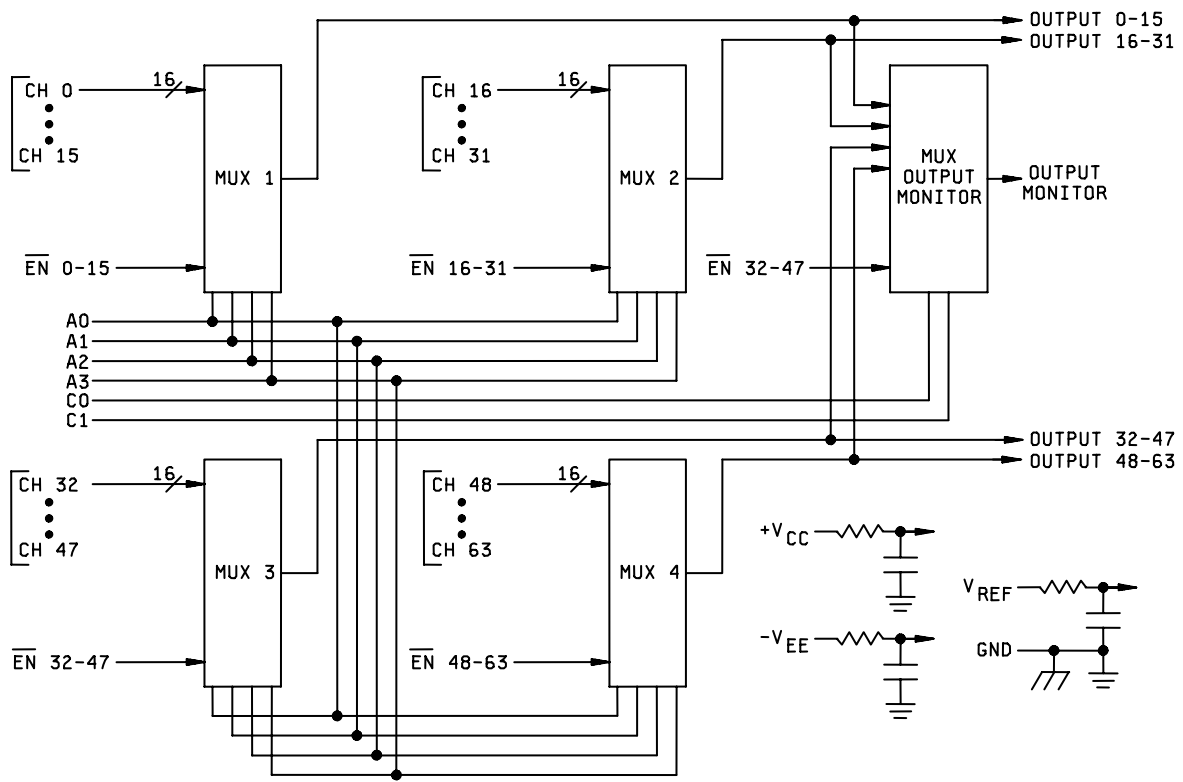


FIGURE 5. Block diagram, (Device type 02) - Continued.

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TABLE II. Electrical test requirements.

MIL-PRF-38534 test requirements	Subgroups (in accordance with MIL-PRF-38534, group A test table)
Interim electrical parameters	1, 9
Final electrical parameters	1*, 2, 3, 9, 10, 11
Group A test requirements	1, 2, 3, 9, 10, 11
Group C end-point electrical parameters	1, 9
End-point electrical parameters for radiation hardness assurance (RHA) devices	Not applicable

* PDA applies to subgroup 1.

4. VERIFICATION

4.1 Sampling and inspection. Sampling and inspection procedures shall be in accordance with MIL-PRF-38534 or as modified in the device manufacturer's Quality Management (QM) plan. The modification in the QM plan shall not affect the form, fit, or function as described herein.

4.2 Screening. Screening shall be in accordance with MIL-PRF-38534. The following additional criteria shall apply:

- a. Burn-in test, method 1015 of MIL-STD-883.
 - (1) Test condition A, B, C, or D. The test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to either DSCC-VA or the acquiring activity upon request. Also, the test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in method 1015 of MIL-STD-883.
 - (2) T_A as specified in accordance with table I of method 1015 of MIL-STD-883.
- b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.

4.3 Conformance and periodic inspections. Conformance inspection (CI) and periodic inspection (PI) shall be in accordance with MIL-PRF-38534 and as specified herein.

4.3.1 Group A inspection (CI). Group A inspection shall be in accordance with MIL-PRF-38534 and as follows:

- a. Tests shall be as specified in table II herein.
- b. Subgroups 4, 5, 6, 7, and 8 shall be omitted.

4.3.2 Group B inspection (PI). Group B inspection shall be in accordance with MIL-PRF-38534.

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4.3.3 Group C inspection (PI). Group C inspection shall be in accordance with MIL-PRF-38534 and as follows:

- a. End-point electrical parameters shall be as specified in table II herein.
- b. Steady-state life test, method 1005 of MIL-STD-883.
 - (1) Test condition A, B, C, or D. The test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to either DSCC-VA or the acquiring activity upon request. Also, the test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in method 1005 of MIL-STD-883.
 - (2) T_A as specified in accordance with table I of method 1005 of MIL-STD-883.
 - (3) Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.

4.3.4 Group D inspection (PI). Group D inspection shall be in accordance with MIL-PRF-38534.

4.3.5 Radiation Hardness Assurance (RHA) inspection. RHA inspection is not currently applicable to this drawing.

5. PACKAGING

5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-PRF-38534.

6. NOTES

6.1 Intended use. Microcircuits conforming to this drawing are intended for use for Government microcircuit applications (original equipment), design applications, and logistics purposes.

6.2 Replaceability. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.

6.3 Configuration control of SMD's. All proposed changes to existing SMD's will be coordinated as specified in MIL-PRF-38534.

6.4 Record of users. Military and industrial users shall inform Defense Supply Center Columbus (DSCC) when a system application requires configuration control and the applicable SMD. DSCC will maintain a record of users and this list will be used for coordination and distribution of changes to the drawings. Users of drawings covering microelectronic devices (FSC 5962) should contact DSCC-VA, telephone (614) 692-0544.

6.5 Comments. Comments on this drawing should be directed to DSCC-VA, Columbus, Ohio 43218-3990, or telephone (614) 692-1081.

6.6 Sources of supply. Sources of supply are listed in MIL-HDBK-103 and QML-38534. The vendors listed in MIL-HDBK-103 and QML-38534 have submitted a certificate of compliance (see 3.7 herein) to DSCC-VA and have agreed to this drawing.

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STANDARD MICROCIRCUIT DRAWING BULLETIN

DATE: 05-03-03

Approved sources of supply for SMD 5962-05209 are listed below for immediate acquisition information only and shall be added to MIL-HDBK-103 and QML-38534 during the next revisions. MIL-HDBK-103 and QML-38534 will be revised to include the addition or deletion of sources. The vendors listed below have agreed to this drawing and a certificate of compliance has been submitted to and accepted by DSCC-VA. This bulletin is superseded by the next dated revisions of MIL-HDBK-103 and QML-38534. DSCC maintains an online database of all current sources of supply at <http://www.dscclia.mil/Programs/Smcr/>.

Standard microcircuit drawing PIN <u>1/</u>	Vendor CAGE number	Vendor similar PIN <u>2/</u>
5962-0520901KXC	88379	ACT8504-S
5962-0520902KXC	88379	ACT8505-S

- 1/ The lead finish shown for each PIN representing a hermetic package is the most readily available from the manufacturer listed for that part. If the desired lead finish is not listed contact the Vendor to determine its availability.
- 2/ **Caution.** Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.

Vendor CAGE
number

88379

Vendor name
and address

Aeroflex Laboratories, Incorporated
35 South Service Road
Plainview, NY 11803-4193

The information contained herein is disseminated for convenience only and the Government assumes no liability whatsoever for any inaccuracies in the information bulletin.